

Final Product Change Notification

Issue Date: 18-Nov-2018 Effective Date: 16-Feb-2019

Here's your personalized quality information concerning products Digi-Key purchased from NXP.

For detailed information we invite you to view this notification online

201810025F01



Management Summary

Completion of MST Final Test Platform expansion / relocation from the NXP ATTJ Tianjin, China test site to the KESM Industries Tianjin, China test site for supply assurance.

Change Category

[] Wafer Fab Process	[] Assembly [] F	Product Marking	[X] Test	[] Design
	Process	· ·	Location	0
[] Wafer Fab Materials	[] Assembly [] N	Mechanical Specification	[]Test	[] Errata
	Materials		Process	
[] Wafer Fab Location	[] Assembly []		[] Test	[] Electrical
	Location Page	cking/Shipping/Labeling	Equipment	spec./Test
				coverage
[] Firmware	[]Other			

MST Final Test Platform Expansion / Relocation from ATTJ to KESM - Completion

Description of Change

Previously NXP Semiconductors announced with PCN 201704014F01 from April 2017, the first phase of the MST Final Test platform expansion / relocation from the NXP ATTJ Tianjin, China test site to the KESM Industries Tianjin, China test site. Additional floor space was required at the ATTJ site for newer / more complex test platforms and resulted in the relocation of the legacy MST test platform and associated hardware to KESM.

NXP Semiconductors now announces with this PCN 201810025F01 the completion of this expansion / relocation for the remaining products. So, this is a completion of the previously announced test site expansion, for the remaining products that were not included in the first phase. Most customers already have approved the first phase activity, as announced in PCN 201704014F01.

Please see the attached qualification results and change summary for additional details.

Reason for Change

Qualification of KESM Industries Tianjin, China is required for customer supply assurance.

Identification of Affected Products

Product identification does not change

Product Availability

Sample Information

Production

Planned first shipment 16-Feb-2019

Anticipated Impact on Form, Fit, Function, Reliability or Quality

No impact on form, fit, function, reliability or quality.

Disposition of Old Products

Existing inventory will be shipped until depleted

Related Notifications

Notification Issue Date Effective Date Title

201704014F01 30-Apr-2017 14-Jun-2017 MST Final Test Platform Expansion / Relocation from ATTJ to KESM

Timing and Logistics

In compliance with JEDEC J-STD-046, your acknowledgement of this change is expected by 18-Dec-2018.

Contact and Support

For all inquiries regarding the ePCN tool application or access issues, please contact NXP "Global Quality Support Team".

For all Quality Notification content inquiries, please contact your local NXP Sales Support team.

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Customer Focus, Passion to Win.

NXP Quality Management Team.

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NXP Semiconductors

High Tech Campus, 5656 AG Eindhoven, The Netherlands

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Affected Part Numbers

MC33662BLEF

MC33660BEFR2

MC33660BEF

MC33897CTEFR2

MCZ33897TEFR2

MC33897CTEF

MC33662LEF